

Best Much for Iddq Measurement and EMMI/OBIRCH

Compact LSI Tester

HPG-3000N series

<Dynamic/Static Iddq Measurement> <Logic Test>
 < Possible to Compile from General LSI Tester >

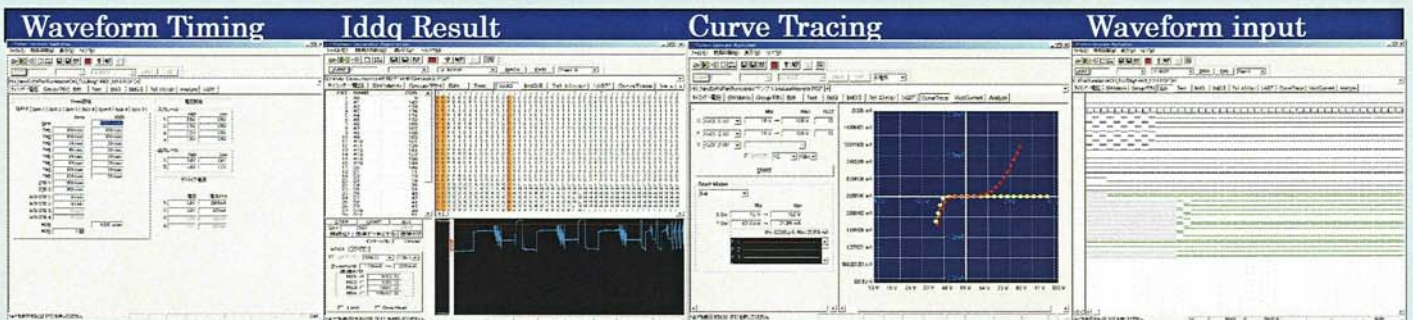
Overview

In Failure Analysis of the LSI, many types of equipment are used. The use of this equipment can easily create the pattern data and the timing data, which is necessary for the semiconductor device to analyze defect/fault. This equipment has the match function which compares pin assignment. The "HPG-3000N" system is compatible with the general LSI tester, thus it can read each "pattern" and "timing" file. "HPG-3000N" can be used in "ADVAN", "ANDO" and "HP" models at present. Other special requirement will be also available.

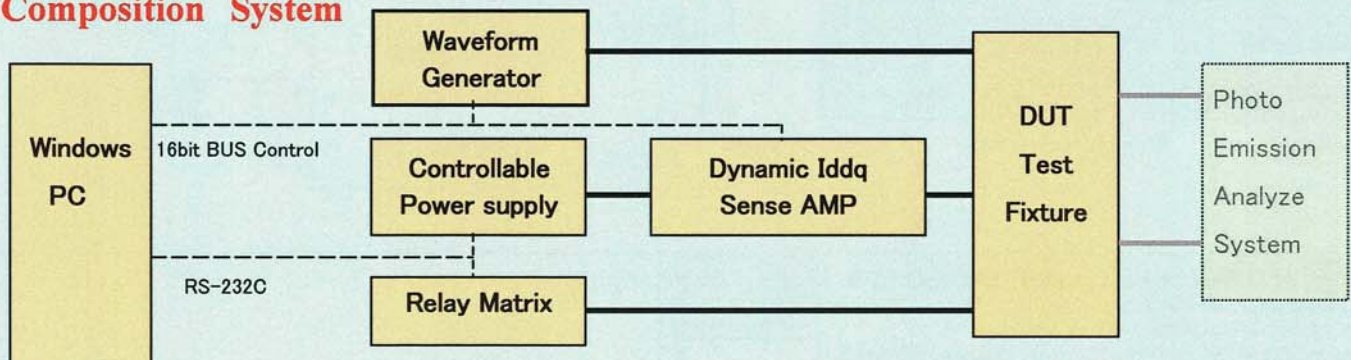


Features

1. Checking the Logic and Function test
2. Measurement the Dynamic Iddq
3. Best matching EMMI/OBIRCH analyze
4. Automatic Curve Tracing and Open / Short testing
5. Operating on the Condition of "General LSI Tester"
6. Shmoo Plot: Standard



Composition System



Specification

Generator Unit	Count pins	128p, 256p, 512p, 768p, 1024p	
	Test rate	100ns to 1.3ms	
	Timing	Clock phase (setting)	8 phase (20ns to 1.3ms)
		Read strobe (setting)	2 phase (20ns to 1.3ms)
		Split Level	8 Level
		Timing skew accuracy	MAX +/-5ns
	Pattern Data	Pattern/Match data memory	128k/512k/2M vector
		Fail Log Memory	128k vector
		Waveform Mode	RZ, NRZ, RTO
		Match Mode	OK
		OP Code	JUMP, LOOP, MUTCH, MUTCH-JUMP, etc.
	Data level	Hi Input level Setting (Vih)	4 pair 0V to +10V (0.1Vstep)
		Low Input level Setting (Vil)	4 pair -2V to +2V (0.1Vstep)
		Drive current	+/- 10mA / pin
		Comparator Judge Voltage Setting (Voh / Vol)	2 pair -1V to +7V (0.1Vstep)
Output resistance		50 ohm	
Pull up/down resistance		4.7 k ohm	
Power Supply Unit	Power supply	MAX 8Vcc	
	Output voltage Setting (accuracy)	+/-0.1V to +/-10V (+/-5mV)	
	Output current Limit Setting (accuracy)	+/- 0.1mA to +/-1A (1% of full scale range)	
	Resistance for changing "I / V"	0.1ohm, 1ohm, 10ohm, 100ohm, 1kohm, 10kohm (Choice from 6 kinds)	
	Current measurement range 1 (16bit ADC.)	1A, 100mA, 10mA, 1mA, 100uA, 10uA, 1uA, 100nA	
	Current measurement range 2 (12bit ADC.)	1A, 100mA, 10mA, 1mA, 100uA	
	Current measurement resolution	1/2000	
	Current measurement accuracy	0.5% of full scale range	
Sense AMP	Iddq Sampling rate	100ns to 1.3 ms	
	Iddq Sampling strobe	20ns to 1.3ms	
	Iddq Resistance for changing "I / V"	0.1 ohm, 1 ohm, 10 ohm, 100 ohm: choice from 4 kinds	
	Dynamic Iddq measurement range	1A, 100mA, 10mA, 1mA	
	Dynamic Iddq measurement resolution	1/256	
	Dynamic Iddq measurement accuracy	2% of full scale range	
Size	600(W) * 700(D) * 850(H)	*PC no contained	
Weight	60kg to 100kg		
Control	RS-232C and 16bit Bus		
OS	Windows 2000/XP		
Power	AC100V/ 115V	7A 50/60Hz	

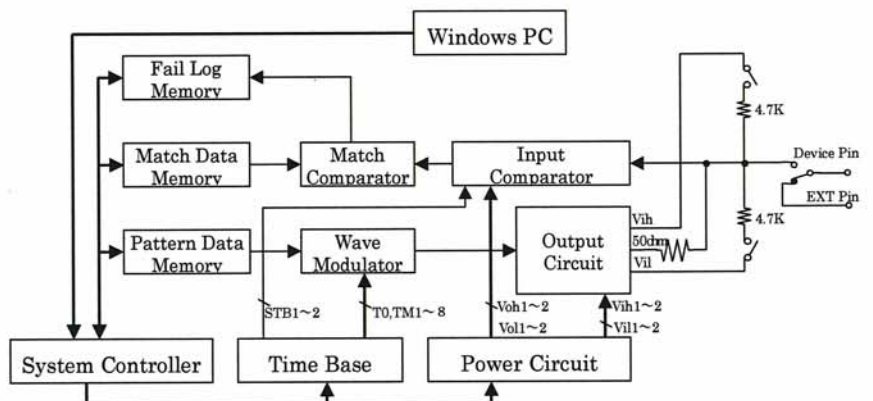
Model

Model	Pin	Memory
HPG-3128NF (128KW)	128	128K vector
HPG-3128NF (512KW)	128	512K vector
HPG-3128NF (2MW)	128	2M vector
HPG-3256NF (128KW)	256	128K vector
HPG-3256NF (512KW)	256	512K vector
HPG-3256NF (2MW)	256	2M vector

*PC contained

*Possible to Pin upgrade

HPG-3000N Block diagram



HANWA HANWA ELECTRONIC IND.CO.LTD
 Headquarters: 689-3, Ogaito, Wakayama Pref.649-6272, Japan
 TEL +81-73-477-4435 FAX +81-73-477-3445
 Kumamoto Plant: Itakusu, 2840, Mikawa-gun, Kumamoto Pref. 861-0913
 TEL +81-968-34-3339 FAX +81-968-34-3369
<http://www.hanwa-ei.co.jp/> info@hanwa-ei.co.jp



Agent